

<b>Notice of References Cited</b>	Application/Control No. 10/657,776	Applicant(s)/Patent Under Reexamination SNOW ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0104129	06-2004	Gu et al.	205/775
	B	US-2004/0067530	04-2004	Gruner, George	435/007.1
	C	US-2004/0041154	03-2004	Watanabe et al.	257/077
	D	US-6,528,020	03-2003	Dai et al.	422/98
	E	US-2003/0198812	10-2003	Rueckes et al.	428/408
	F	US-2003/0098640	05-2003	Kishi et al.	313/309
	G	US-2003/0068432	04-2003	Dai et al.	427/58
	H	US-2003/0058697	03-2003	Tour et al.	365/200
	I	US-2002/0172639	11-2002	Horiuchi et al.	423/447.2
	J	US-2002/0158342	10-2002	Tuominen et al.	257/784
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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